## CS 4495 Computer Vision RANdom SAmple Consensus

Aaron Bobick
School of Interactive
Computing


## Administrivia

- PS 3:
- Check Piazza - good conversations. In fact some pretty explicit solutions...
- The F matrix: the actual numbers may vary quite a bit. But check the epipolar lines you get.
- Normalization: read extra credit part. At least try removing the centroid. Since we're using homogenous coordinates (2D homogenous have 3 elements) it's easy to have a transformation matrix that subtracts off an offset.
- Go back an recheck slides: A 3 vector in these projective geometry is both a point and a line.


## Matching with Features

- Want to compute transformation from one image to the other
- Overall strategy:
- Compute features
- Match matching features (duh?)
- Compute best transformation (translation, affine, homography) from matches



## An introductory example:

## Harris corner detector


C.Harris, M.Stephens. "A Combined Corner and Edge Detector". 1988

## Harris Detector: Mathematics

$$
M=\sum_{x, y} w(x, y)\left[\begin{array}{cc}
I_{x}^{2} & I_{x} I_{y} \\
I_{x} I_{y} & I_{y}^{2}
\end{array}\right]
$$

Measure of corner response:

$$
R=\operatorname{det} M-\alpha(\operatorname{trace} M)^{2}
$$

$$
\begin{aligned}
\operatorname{det} M & =\lambda_{1} \lambda_{2} \\
\operatorname{trace} M & =\lambda_{1}+\lambda_{2}
\end{aligned}
$$

( $\alpha$ - empirical constant, typically 0.04-0.06)

## Harris corner response function

$$
R=\operatorname{det}(M)-\alpha \operatorname{trace}(M)^{2}=\lambda_{1} \lambda_{2}-\alpha\left(\lambda_{1}+\lambda_{2}\right)^{2}
$$

- $R$ depends only on eigenvalues of M , but don't compute them (no sqrt, so really fast!
- $R$ is large for a corner
- $R$ is negative with large magnitude for an edge
- $|R|$ is small for a flat region



## Key point localization

- General idea: find robust extremum (maximum or minimum) both in space and in scale.
- SIFT specific suggestion: use DoG pyramid to find maximum values (remember edge detection?) - then eliminate "edges" and pick only corners.
- More recent: use Harris detector to find maximums in space and then look at the Laplacian pyramid (we'll do this later) for maximum in scale.


Each point is compared to its 8 neighbors in the current image and 9 neighbors each in the scales above and below.

## Point Descriptors

- We know how to detect points
- How to match them? Two parts:
- Compute a descriptor for each and make the descriptor both as invariant and as distinctive as possible. (Competing goals) SIFT one example.



## Idea of SIFT

- Image content is transformed into local feature coordinates that are invariant to translation, rotation, scale, and other imaging parameters



## SIFT Features

## SIFT vector formation

- $4 \times 4$ array of gradient orientation histograms over $4 \times 4$ pixels
- not really histogram, weighted by magnitude
- 8 orientations x $4 \times 4$ array $=128$ dimensions
- Motivation: some sensitivity to spatial layout, but not too much.

showing only 2 x 2 here but is $4 \times 4$


## Point Descriptors

- We know how to detect points
- How to match them? Two parts:
- Compute a descriptor for each and make the descriptor both as invariant and as distinctive as possible. (Competing goals) SIFT one example
- Need to figure out which point matches which..



## Feature-based alignment outline



- Extract features


## Feature-based alignment outline



- Extract features
- Compute putative matches - e.g. "closest descriptor"


## Feature-based alignment outline



- Extract features
- Compute putative matches - e.g. "closest descriptor"
- Loop:
- Hypothesize transformation $T$ from some matches


## Feature-based alignment outline



- Extract features
- Compute putative matches- e.g. "closest descriptor"
- Loop:
- Hypothesize transformation $T$ from some matches
- Verify transformation (search for other matches consistent with $T$ )


## Feature-based alignment outline



- Extract features
- Compute putative matches- e.g. "closest descriptor"
- Loop:
- Hypothesize transformation $T$ from some matches
- Verify transformation (search for other matches consistent with $T$ )
- Apply transformation


## How to get "putative" matches?

## Feature matching

- Exhaustive search
- for each feature in one image, look at all the other features in the other image(s) - pick best one
- Hashing
- compute a short descriptor from each feature vector, or hash longer descriptors (randomly)
- Nearest neighbor techniques
- k-trees and their variants


## Feature-space outlier rejection

- Let's not match all features, but only these that have "similar enough" matches?
- How can we do it?
- SSD(patch1,patch2) < threshold
- How to set threshold?



## Feature-space outlier rejection

- A better way [Lowe, 1999]:
- 1-NN: SSD of the closest match
- 2-NN: SSD of the second-closest match
- Look at how much better 1-NN is than 2-NN, e.g. 1-NN/2-NN
- That is, is our best match much better than the next?



## Feature matching

- Exhaustive search
- for each feature in one image, look at all the other features in the other image(s) - pick best one
- Hashing
- compute a short descriptor from each feature vector, or hash longer descriptors (randomly)
- Nearest neighbor techniques
- $k$-trees and their variants
- But...
- Remember: distinctive vs invariant competition? Means:
- Problem: Even when pick best match, still lots (and lots) of wrong matches - "outliers"


## Another way to remove mistakes

- Why are we doing matching?
- To compute a model of the relation between entities
- So this is really "model fitting"


## Fitting

- Choose a parametric model to represent a set of features - remember this???

simple model: lines simple model: circles

complicated model: car


## Fitting: Issues

Case study: Line detection


- Noise in the measured feature locations
- Extraneous data: clutter (outliers), multiple lines
- Missing data: occlusions


## Total least squares

-Distance between point $\left(x_{i}, y_{i}\right)$ and line $a x+b y=d$ $\left(a^{2}+b^{2}=1\right):$

$$
\left|a x_{i}+b y_{i}-d\right|
$$



## Total least squares

-Distance between point $\left(x_{i}, y_{i}\right)$ and line $a x+b y=d$ $\left(a^{2}+b^{2}=1\right)$ :

$$
\left|a x_{i}+b y_{i}-d\right|
$$

- Find ( $\mathrm{a}, \mathrm{b}, \mathrm{d}$ ) to minimize the
 perpendicular distances

$$
E=\sum_{i=1}^{n}\left(a x_{i}+b y_{i}-d\right)^{2}
$$

## Least squares as likelihood maximization

- Generative model: line points are corrupted by Gaussian noise in the direction perpendicular to the line

$$
\binom{x}{y}=\binom{u}{v}+\varepsilon\binom{a}{b}
$$



## Least squares as likelihood maximization

- Generative model: line points are corrupted by Gaussian noise in the direction perpendicular to the line

$$
\binom{x}{y}=\binom{u}{v}+\varepsilon\binom{a}{b}
$$



Likelihood of points given line parameters ( $a, b, d$ ):
$P\left(x_{1}, y_{1}, \ldots, x_{n}, y_{n} \mid a, b, d\right)=\prod_{i=1}^{n} P\left(x_{i}, y_{i} \mid a, b, d\right) \propto \prod_{i=1}^{n} \exp \left(-\frac{\left(a x_{i}+b y_{i}-d\right)^{2}}{2 \sigma^{2}}\right)$
Log-likelihood: $L\left(x_{1}, y_{1}, \ldots, x_{n}, y_{n} \mid a, b, d\right)=-\frac{1}{2 \sigma^{2}} \sum_{i=1}^{n}\left(a x_{i}+b y_{i}-d\right)^{2}$

Least squares: Lack of robustness to (very) non-Gaussian noise

- Least squares fit to the red points:



## Least squares: Lack of robustness to (very) non-Gaussian noise

- Least squares fit with an outlier:


Problem: squared error heavily penalizes outliers

## Robust estimators

- General approach: minimize

$$
\sum_{i} \rho\left(r_{i}\left(x_{i}, \theta\right) ; \sigma\right)
$$

$r_{i}\left(x_{i}, \theta\right)$ - residual of ith point w.r.t. model parameters $\theta$ $\rho$ - robust function with scale parameter $\sigma$


The robust function $\rho$ behaves like squared distance for small values of the residual $u$ but saturates for larger values of $u$

## Choosing the scale: Just right



The effect of the outlier is minimized

## Choosing the scale: Too small



The error value is almost the same for every point and the fit is very poor

## Choosing the scale: Too large



Behaves much the same as least squares

## "Find consistent matches"???

- Some points (many points) are static in the world
- Some are not
- Need to find the right ones so can compute pose.
- Well tried approach:
- Random Sample Consensus (RANSAC)


## Simpler Example

- Fitting a straight line



## Discard Outliers

- Assume few real points with distance $d>\theta$
- RANSAC:
- RANdom SAmple Consensus
- Fischler \& Bolles 1981
- Copes with a large proportion of outliers
M. A. Fischler, R. C. Bolles. Random Sample Consensus: A Paradigm for Model Fitting with Applications to Image Analysis and Automated Cartography. Comm. of the ACM, Vol 24, pp 381-395, 1981.


## RANSAC

(RANdom SAmple Consensus)

## Algorithm:

1. Sample (randomly) the number of points required to fit the model
2. Solve for model parameters using sample
3. Score by the fraction of inliers within a preset threshold of the model

Repeat 1-3 until the best model is found with high confidence

## RANSAC

 Line fitting example

## Algorithm:

1. Sample (randomly) the number of points required to fit the model (\#=2)
2. Solve for model parameters using sample
3. Score by the fraction of inliers within a preset threshold of the model

Repeat 1-3 until the best model is found with high confidence

## RANSAC

 Line fitting example

## Algorithm:

1. Sample (randomly) the number of points required to fit the model (\#=2)
2. Solve for model parameters using sample
3. Score by the fraction of inliers within a preset threshold of the model

Repeat 1-3 until the best model is found with high confidence

## RANSAC

 Line fitting example

Algorithm:

1. Sample (randomly) the number of points required to fit the model (\#=2)
2. Solve for model parameters using the sample
3. Score by the fraction of inliers within a preset threshold of the model

Repeat 1-3 until the best model is found with high confidence

## RANSAC

 Line fitting exampleAlgorithm:


1. Sample (randomly) the number of points required to fit the model (\#=2)
2. Solve for model parameters using sample
3. Score by the fraction of inliers within a preset threshold of the model

Repeat 1-3 until the best model is found with high confidence

## The fundamental RANSAC assumption:

More support implies better fit.

## RANSAC for general model

- A given model has a minimal set - the smallest number of samples from which the model can be computed.
- Line: 2 points
- Image transformations are models. Minimal set of $s$ of point pairs/matches:
- Trans/ation: pick one point pair
- Homography (for plane) - pick 4 point pairs
- Fundamental matrix - pick 8 point pairs (really 7 but lets not go there)
- Algorithm
- Randomly select s points (or point pairs) to form a sample
- Instantiate a model
- Get consensus set $C_{i}$
- If $\left|C_{i}\right|>T$, terminate and return model
- Repeat for $N$ trials, return model with max $\left|C_{i}\right|$


## Distance Threshold

- Let's assume location noise is Gaussian with $\sigma^{2}$
- Then the distance $d$ has Chi distribution with k degrees of freedoms where $k$ is the dimension of the Gaussian.
-If one dimension, e.g.distance off a line, then 1DOF

$$
f(d)=\frac{\sqrt{2} e^{-\left(\frac{d^{2}}{2 \sigma^{2}}\right)}}{\sqrt{\pi} \sigma}, d \geq 0
$$



## Distance Threshold

For $95 \%$ cumulative threshold $t$ when Gaussian with $\sigma^{2}$

$$
t^{2}=3.84 \sigma^{2}
$$

That is: if $t^{2}=3.84 \sigma^{2}$ then $95 \%$ probability that $d<t$ when point is inlier

But...

Usually set by "empirically"...

## How many samples should we try?

- We want: at least one sample with all inliers
- With random samples we can't guarantee. But with probability $p$ we can, e.g. $p=0.99$


## Choosing the parameters

- Initial number of points $s$
- Typically minimum number needed to fit the model
- Distance threshold $t$
- Choose $t$ so probability for inlier is high (e.g. 0.95)
- If zero-mean Gaussian noise with std. dev. $\sigma: t^{2}=$ $3.84 \sigma^{2}$
- Number of samples $N$
- Choose $N$ so that, with probability $p$, at least one random sample is free from outliers (e.g. $p=0.99$ )
- Need to set $N$ based on outlier ratio: $e$


## Calculate N

1. $s$ - number of points to compute solution
2. $p$-probability of success
3. $e$-proportion outliers, so $\%$ inliers $=(1-e)$
4. $\quad P($ sample set with all inliers $)=(1-e)^{s}$
5. $P($ sample set will have at least one outlier $)=$

$$
\left(1-(1-e)^{s}\right)
$$

6. $\quad P($ all $N$ samples have outlier $)=\left(1-(1-e)^{s}\right)^{N}$
7. We want $P($ all $N$ samples have outlier $)<(1-p)$
8. So: $\left(1-(1-e)^{s}\right)^{N}<(1-p)$

$$
N>\log (1-p) / \log \left(1-(1-e)^{s}\right)
$$

## $N$ for probability $p$ of at least one sample with only inliers

$$
N>\log (1-p) / \log \left(1-(1-e)^{s}\right)
$$

- Set p=0.99 - chance of getting good sample

$$
\begin{array}{ll}
s=2, e=5 \% & \Rightarrow \mathrm{~N}=2 \\
s=2, e=50 \% & \Rightarrow \mathrm{~N}=17 \\
s=4, e=5 \% & \Rightarrow \mathrm{~N}=3 \\
s=4, e=50 \% & \Rightarrow \mathrm{~N}=72 \\
s=8, e=5 \% & \Rightarrow \mathrm{~N}=5 \\
s=8, e=50 \% & \Rightarrow \mathrm{~N}=1177
\end{array}
$$

| proportion of outliers $e$ |  |  |  |  |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| s | $5 \%$ | $10 \%$ | $20 \%$ | $25 \%$ | $30 \%$ | $40 \%$ | $50 \%$ |  |
| 2 | 2 | 3 | 5 | 6 | 7 | 11 | 17 |  |
| 3 | 3 | 4 | 7 | 9 | 11 | 19 | 35 |  |
| 4 | 3 | 5 | 9 | 13 | 17 | 34 | 72 |  |
| 5 | 4 | 6 | 12 | 17 | 26 | 57 | 146 |  |
| 6 | 4 | 7 | 16 | 24 | 37 | 97 | 293 |  |
| 7 | 4 | 8 | 20 | 33 | 54 | 163 | 588 |  |
| 8 | 5 | 9 | 26 | 44 | 78 | 272 | 1177 |  |

- $N$ increases steeply with s


## $N$ for probability $p$ of at least one sample with only inliers

$$
N>\log (1-p) / \log \left(1-(1-e)^{s}\right)
$$

- Set p=0.99 - chance of getting good sample

$$
\begin{array}{ll}
s=2, e=5 \% & \Rightarrow \mathrm{~N}=2 \\
s=2, e=50 \% & \Rightarrow \mathrm{~N}=17 \\
s=4, e=5 \% & \Rightarrow \mathrm{~N}=3 \\
s=4, e=50 \% & \Rightarrow \mathrm{~N}=72 \\
s=8, e=5 \% & \Rightarrow \mathrm{~N}=5 \\
s=8, e=50 \% & \Rightarrow \mathrm{~N}=1177
\end{array}
$$



- $N$ increases steeply with s


## How big does N need to be?

$$
N>\log (1-p) / \log \left(1-(1-e)^{s}\right)
$$

- So $N=f(e, s, p)$
- What is $N$ not a function of?
$N=f(e, s, p)$, but not the number
of points(matches)!


## Matching features



What do we do about the "bad" matches?

## RAndom SAmple Consensus (1)



Select one match, count inliers

## RAndom SAmple Consensus (2)



Select one match, count inliers

## Least squares fit



## 2D transformation models

2 matches:
Similarity
(translation,
scale, rotation)

3 matches:
Affine


## RANSAC for estimating, say, homography

RANSAC loop:

1. Select four feature pairs (at random)
2. Compute homography $\boldsymbol{H}_{\mathrm{k}}$ (exact)
3. Compute inliers where $\operatorname{SSD}\left(p_{i}{ }^{\prime}, \boldsymbol{H}_{\mathrm{k}} p i\right)<\varepsilon$
4. Keep $\boldsymbol{H}_{\boldsymbol{k}}$, if $C_{\boldsymbol{k}}$ is the largest set of inliers
5. For a while go to 1
6. Re-compute least-squares $\boldsymbol{H}$ estimate on all of the $C_{k}$ inliers

## Adaptively determining the number of samples

- Inlier ratio $e$ is often unknown a priori, so pick worst case, e.g. 50\%, and adapt if more inliers are found, e.g. $80 \%$ would yield $\mathrm{e}=0.2$
- Adaptive procedure:
- $\mathrm{N}=\infty$, sample_count $=0, e=1.0$
- While N >sample_count
- Choose a sample and count the number of inliers
- Set $\mathrm{e}_{0}=1$ - (number of inliers)/(total number of points)
- If $e_{0}<e$ Set $e=e_{0}$ and recompute $N$ from $e$ :

$$
N=\log (1-p) / \log \left(1-(1-e)^{s}\right)
$$

- Increment the sample_count by 1


## RANSAC for recognition



## RANSAC for fundamental matrix



## Putative matches (motion) by cross-correlation (188)



## RANSAC for fundamental matrix

Inliers (99)
Outliers (89)


## Point cloud planes



Find the plane and object in realtime


## 2D transformation models

- Similarity (translation, scale, rotation)

- Affine

- Projective (homography)


## RANSAC conclusions

The good...

- Simple and general
- Applicable to many different problems, often works well in practice
- Robust to large numbers of outliers
- Applicable for larger number of parameters than Hough transform
- Parameters are easier to choose than Hough transform


## RANSAC conclusions

The not-so-good...

- Computational time grows quickly with the number of model parameters
- Sometimes problematic for approximate models


## RANSAC conclusions

Common applications

- Computing a homography (e.g., image stitching) or other image transform
- Estimating fundamental matrix (relating two views)
- Pretty much every problem in robot vision

